269	arch Notes
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Application/Control No.	Applicant(s)/Patent under Reexamination
10/671,563	BYUN, YOUNG-KWANG
Examiner	Art Unit
Khoa D. Huynh	3751

	SEAR	CHED	
Class	Subclass	Date	Examiner
401	123-129	12/5/2005	нк
132	293-297	12/5/2005	нк
132	313,314	12/5/2005	нк
132	317	12/5/2005	нк
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
interference search, see print out	12/5/2005	нк	